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L5	39	"control flow" with "basic blocks" and 717/124-135.ccls.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/05/25 18:43
L4	0	"control flow" with "basic blocks" same coverage	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/05/25 18:43
L3	308	"control flow" with "basic blocks"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/05/25 18:43
L2	1	"path coverage" same "basic blocks"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/05/25 18:42
S39	8	S37 and S38	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/05/25 18:09
L1	116	"path coverage"	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/05/25 18:09
S38	682	(717/124,126).CCLS.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/05/25 15:57
S37	472	formal adj verification	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/05/25 15:57
S36	8	formal adj methods with coverage	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/04/28 15:15
S35	1	coverability and inflator	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/04/28 15:15

S34	116	coverability	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2005/04/28 13:24
S33	2	("20030110474").PN.	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	OFF	2005/04/28 13:19



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IEEE JNL IEEE Journal or Magazine

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IEEE CNF IEEE Conference Proceeding

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IEEE STD IEEE Standard

Select Article Information

- ☐ 1. Automatic test data generation for programs with integer and float variables  
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